



AMENDMENT UNDER 37 CFR 1.116 EXPEDITED PROCEDURE – EXAMINING GROUP 2877

<u>PATENT</u>

Attorney Docket No.: 16869P-042900US Client Ref. No.: 210000749US1

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re application of:

Takenori HIROSE, et al.

Application No.: 10/081,385

Filed: February 20, 2002

For: FILM THICKNESS MEASURING METHOD AND APPARATUS, AND THIN FILM DEVICE MANUFACTURING METHOD AND MANUFACTURING APPARATUS USING SAME

Customer No.: 20350

Confirmation No. 9702

Examiner: Hwa S. Lee

Technology Center/Art Unit: 2877

AMENDMENT UNDER 37 CFR 1.116

EXPEDITED PROCEDURE EXAMINING GROUP 2877

Mail Stop AF

Commissioner for Patents P.O. Box 1450 Alexandria, VA 22313-1450 July 22, 2005

Sir:

In response to the Final Office Action mailed March 9, 2005 on the abovereferenced application, for which a **Petition to Extend Time** for two months is enclosed, please enter the following amendments and remarks:

Amendments to the Specification begin on page 2 of this paper.

Amendments to the Claims are reflected in the listing of claims which begins on page 3 of this paper.

Remarks/Arguments begin on page 9 of this paper.

Enclosures include a Petition under 37 CFR 1.78(a)(3) and a Statement under 37 CFR 1.78(a)(3) following page 13 of this paper.